

**Search Notes**

Application/Control No.

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Examiner

Alex Liew

Applicant(s)/Patent under  
Reexamination

BAN ET AL.

Art Unit

2624

**SEARCHED**

Class	Subclass	Date	Examiner
382	153	2/23/2007	AL

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
382/154 limited to text search	2/23/2007	AL
382/106,153,154 limited to text search	12/19/2007	AL